

Pending											
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#	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval C	Inventor	S	C	P
1	US 20030031058 A1	20030213	165	Semiconductor device formed in a rectangle region on a	365/189.09	257/E23.02; 365/51		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
2	US 20020054514 A1	20020509	168	Semiconductor memory device and defect remedying method	365/189.02	257/E23.02		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
3	US 6657901 B2	20031202	162	Semiconductor device formed in a rectangle region on a	365/189.02	257/E23.02; 365/51;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
4	US 6515913 B2	20030204	160	Semiconductor memory device and defect remedying method	365/189.02	257/E23.02; 365/230.02;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
5	US 6335884 B1	20020101	159	Semiconductor memory device and defect remedying method	365/189.02	257/E23.02; 365/230.02;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
6	US 6212089 B1	20010403	161	Semiconductor memory device and defect remedying method	365/51	257/E23.02; 365/189.01;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
7	US 6178127 B1	20010123	33	Semiconductor memory device allowing reliable repairing	365/200	365/230.03		Haraguchi, Yoshiyuki	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
8	US 6160744 A	20001212	162	Semiconductor memory device and defect remedying method	365/200	365/189.02; 365/230.03;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
9	US 6049500 A	20000411	160	Semiconductor memory device and defect remedying method	365/230.02	257/E23.02; 365/230.03;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
10	US 5995422 A	19991130	10	Redundancy circuit and method of a semiconductor	365/200	365/225.7		Im, Heung-Soo et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
11	US 5854508 A	19981229	161	Semiconductor memory device having zigzag bonding pad	257/786	257/666; 257/784;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
12	US 5602771 A	19970211	160	Semiconductor memory device and defect remedying method	365/51	257/E23.02; 365/230.03;		Kajigaya, Kazuhiko et al.	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>